## Application/Control No. Applicant(s)/Patent Under Reexamination 10/629,917 YONEZAWA, MINORU Notice of References Cited Examiner Art Unit Page 1 of 1 VAN T. PHAM 2627

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0196717	12-2002	Masui et al.	369/44.29
*	В	US-5,475,662	12-1995	Miyagawa et al.	369/44.26
*	С	US-6,768,705	07-2004	Hirai, Yukio	369/44.28
*	D	US-20040218494	11-2004	Lee et al.	369/053.18
*	Ε	US-5,084,848	01-1992	Deguchi et al.	369/44.25
	F	US-			
	G	US-			
	Н	US-			
	i	US-			
	J	US-			
	К	US-		·	
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R					
	တ					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	>	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.